

# PATENT ABSTRACTS OF JAPAN

(11)Publication number : 11-126736

(43)Date of publication of application : 11.05.1999

(51)Int.Cl.

H01L 21/02  
H01L 21/66

(21)Application number : 09-290198

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(22)Date of filing : 23.10.1997

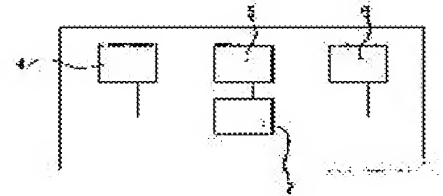
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## (54) APPARATUS AND SYSTEM FOR MANAGING MANUFACTURE OF SEMICONDUCTOR DEVICE

(57)Abstract:

**PROBLEM TO BE SOLVED:** To provide an apparatus for managing manufacture of a semiconductor device which can reliably judge the device by judging the semiconductor manufacture management on the basis of the number of defects in the device.

**SOLUTION:** The apparatus includes a means 4 for detecting the number of defects on a wafer as a defect number, a means 5 for detecting the number of defective ones of chips on the wafer as a defective chip number T, a means 6 for setting a plurality of predetermined regions on the basis of a reference defective chip number T and a reference defect number H as preset references with respect to wafer productivity, and a means 7 for judging that a relationship between the defect number and defective chip number is included in either one of the regions preset by the region setting means 6 to judge acceptance or rejection of the wafer.



## LEGAL STATUS

[Date of request for examination]

06.10.2003

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]